## Amendments to the Claims:

A clean version of the entire set of pending claims, including amendments to the claims, is submitted herewith per 37 CFR 1.121(c)(3). This listing of claims will replace all prior versions, and listings, of claims in the application.

## Listing of Claims:

- (Currently Amended) A method of monitoring the operation of at least one microcontroller unit that is intended for at least one application and is associated with a system wherein, the method comprising;
- -the microcontroller unit has associating at least one non-volatile memory area associated with it-the microcontroller unit, wherein [[-]] the memory area can be read from and written to by the microcontroller unit.[[.]] and
- storing at least one set of statistics relating to the operation of the microcontroller unit, including at least a set of fault statistics for the microcontroller, relating to the operation of the microcontroller unit, can be kept by means of the nonyolatile memory area.
- 2. (Previously Presented) A method as claimed in claim 1, wherein the memory area is permanently supplied by at least one battery unit.
  - 3. (Previously Presented) A method as claimed in claim 1 or 2, wherein
- in relation to the operation of the microcontroller unit a distinction can be made between different reset events, and
- these different reset events can be made accessible to the  $\operatorname{microcontroller}$  unit.
- 4. (Currently Amended) A method as claimed in any of claims 1 to 2, wherein the memory area further comprising:

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-can be permitting the non-volatile memory area to be read from at any time;

and

- ean-be-permitting the non-volatile memory area to written to only after a reset

er-while the system is-restarting starting.

5. (Currently Amended) A base chip for monitoring the operation of at least

one microcontroller unit-that is intended for at least one application, including at least one non-volatile memory area that can be read from and written to by the

one non-volatile memory area that can be read from and written to by the microcontroller unit, and by means of which at least one set of fault statistics relating

to operation of the microcontroller unit, can be produced.

6. (Previously Presented) A base chip as claimed in claim 5, including

- at least one information unit that is provided to allow for different reset

events,

- at least one reset unit for resetting the microcontroller unit, which reset unit is

connected to the microcontroller unit, and

- at least one supply unit that is connected to the microcontroller unit.

7. (Previously Presented) A base chip as claimed in claim 6, wherein

- the memory area and the supply unit are permanently supplied with power

from at least one battery unit, and

- the microcontroller unit has at least one temporary energy supply provided to

it via the supply unit.

8. (Previously Presented) A base chip as claimed in any of claims 6 to 7,

wherein the memory area and the information unit have inserted in front of them at

least one interface unit for the exchange of data with the microcontroller unit.

9. (Previously Presented) A system including at least one microcontroller unit

intended for at least one application and at least one base chip as claimed in any of

claims 5 to 7.

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## 10. (Canceled)

- 11. (Previously Presented) The method of claim 1, wherein the fault statistics include statistics on a plurality of different types of reset events.
- 12. (Previously Presented) The method of claim 11, further comprising: comparing a number of at least one type of reset event to a threshold; and when the number of the at least one type of reset event is greater than the threshold, operating the microcontroller unit in a low-energy mode.
- 13. (Previously Presented) The base chip of claim 5, wherein the at least one non-volatile memory area comprises a random access memory.
- 14. (Previously Presented) The base chip of claim 5, wherein the fault statistics include statistics on a plurality of different types of reset events.
- 15. (Previously Presented) The base chip of claim 14, wherein the base chip is further adapted to compare a number of at least one type of reset event to a threshold, and when the number of the at least one type of reset event is greater than the threshold, operating the microcontroller unit in a low-energy mode.
- 16. (New) The base chip of claim 5, wherein the base chip permits the non-volatile memory area to be read from at any time, and permits the non-volatile memory area to written to only while the system is starting.